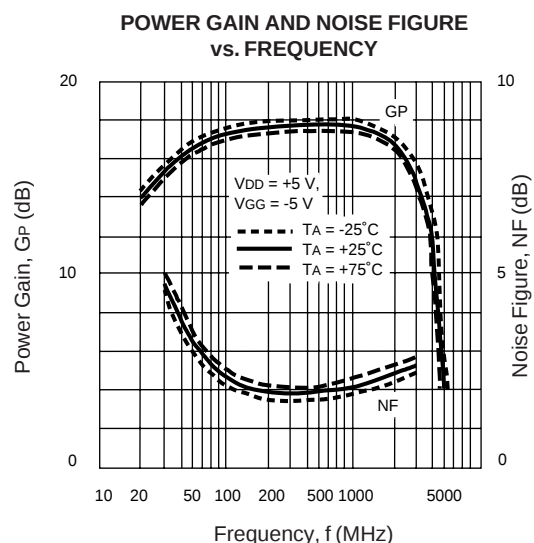


FEATURES

- **ULTRA WIDE BAND:** 50 MHz to 3 GHz
- **LOW NOISE:** 2.7 dB TYP at $f = 50$ MHz to 3 GHz
- **INPUT/OUTPUT IMPEDANCE MATCHED TO 50 Ω**
- **HERMETIC SEALED PACKAGE ASSURES HIGH RELIABILITY**
- **WIDE OPERATING TEMPERATURE RANGE**

DESCRIPTION

The UPG100 is a GaAs monolithic integrated circuit designed as a low noise amplifier from 50 MHz to 3 GHz. This device is suitable for low noise IF gain stages in microwave communication and measurement equipment.



ELECTRICAL CHARACTERISTICS (TA = 25°C, VDD = +5V, VGG = -5 V, f = 0.05 to 3 GHz, ZS = ZL = 50 Ω)

PART NUMBER PACKAGE OUTLINE			UPG100B, UPG100P B08, CHIP		
SYMBOLS	PARAMETERS AND CONDITIONS	UNITS	MIN	TYP	MAX
IDD	Drain Bias Current (RF off)	mA	30	45	60
IGG	Gate Bias Current (RF off)	mA		0.7	1.5
GP	Power Gain	dB	14	16	
Δ GL	Flatness Gain	dB			± 1.5
NF	Noise Figure	dB		2.7	3.5
P1dB	Output Power at 1 dB gain compression point	dBm	+3	+6	
RLIN	Input Return Loss	dB	7	10	
RLOUT	Output Return Loss	dB	7	10	
ISOL	Isolation	dB	30	40	
RTH (CH-C)	Thermal Resistance (Channel to Case)	°C/W			33

ABSOLUTE MAXIMUM RATINGS¹ (T_A = 25°C)

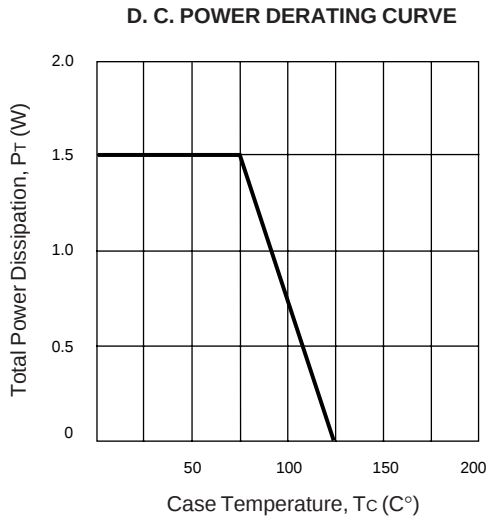
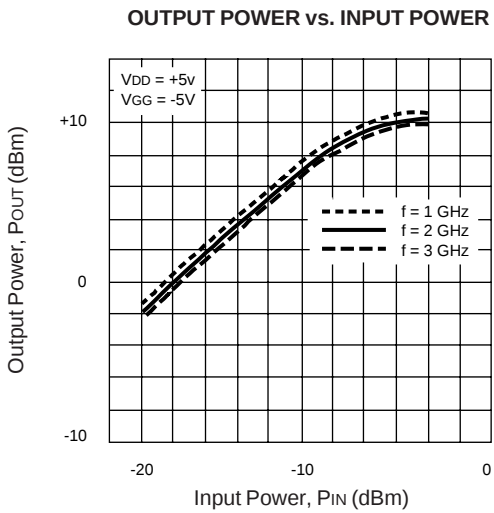
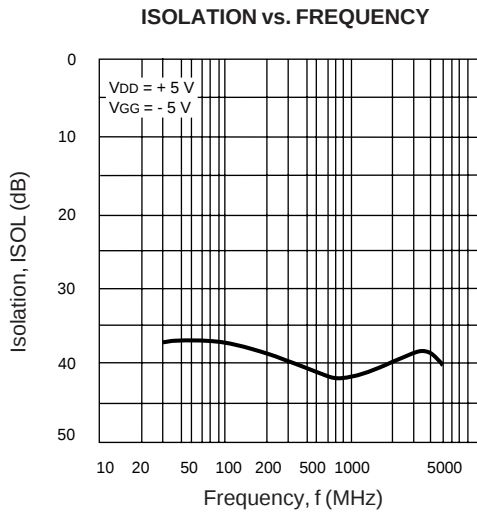
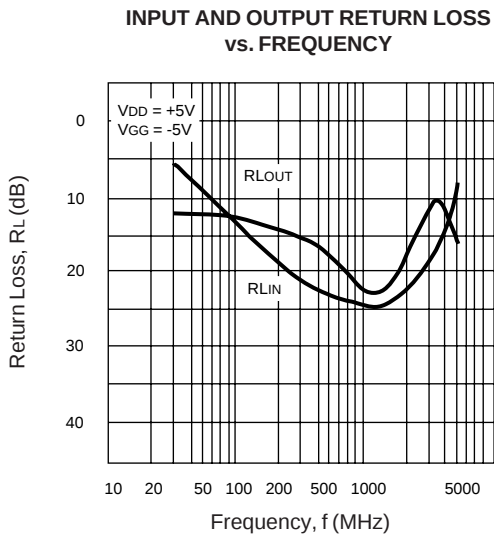
SYMBOLS	PARAMETERS	UNITS	RATINGS
V _{DD}	Drain Voltage	V	+8
V _{GG}	Gate Voltage	V	-8
V _{IN}	Input Voltage	V	-3 to +0.6
P _{IN}	Input Power	dBm	+15
P _T	Total Power Dissipation ²	W	1.5
Top	Operating Temperature	°C	-65 to +125
T _{STG}	Storage Temperature	°C	-65 to +175

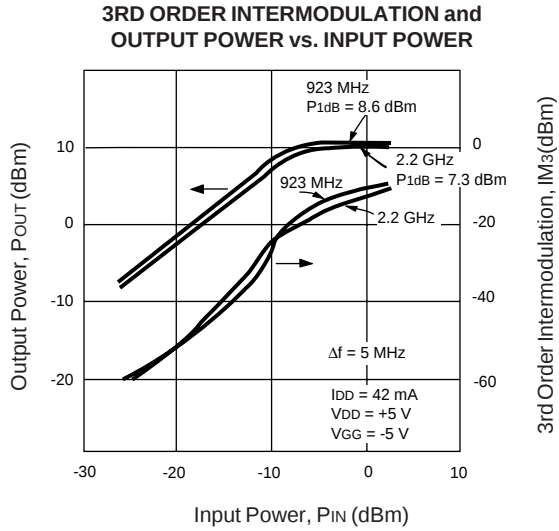
- Notes:
- 1. Operation in excess of any one of these conditions may result in permanent damage.
 - 2. T_{CASE} (T_C) ≤ 125°C

RECOMMENDED
OPERATING CONDITIONS

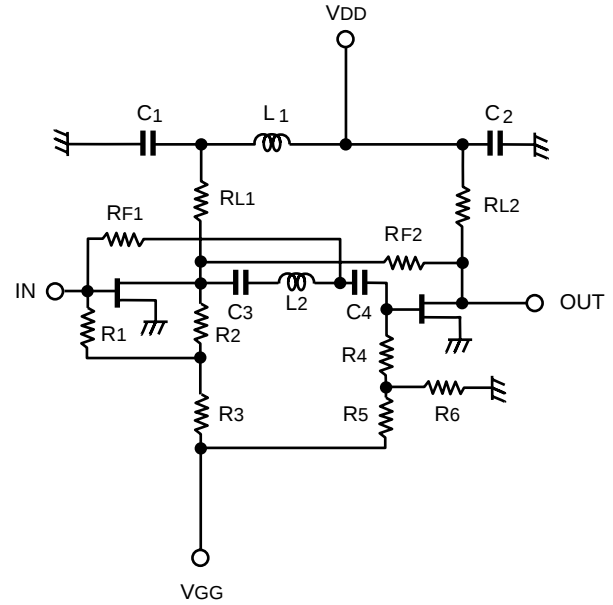
SYMBOLS	PARAMETERS	UNITS	MIN	TYP	MAX
V _{DD}	Drain Voltage	V	4.5	5.0	5.5
V _{GG}	Gate Voltage	V	-5.5	-5.0	-4.5
P _{IN}	Input Power	dBm			10
T _{OP}	Operating Temperature	°C	-50	25	+80

TYPICAL PERFORMANCE CURVES (T_A = 25°C)



TYPICAL PERFORMANCE CURVES (T_A = 25°C)

EQUIVALENT CIRCUIT

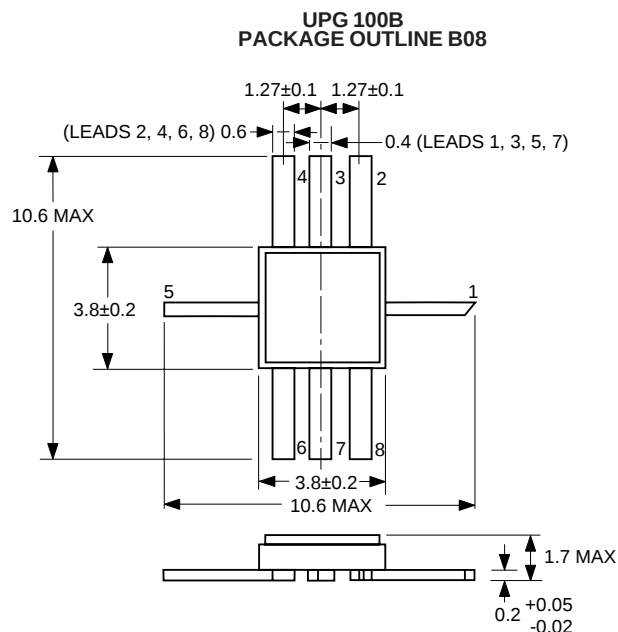
TYPICAL SCATTERING PARAMETERS (T_A = 25°C)

UPG100B

VDD = 5.0 V VGG = -5.0 V

Frequency GHz	S ₁₁		S ₂₁		S ₁₂		S ₂₂		k	S ₂₁ (dB)
	MAG	ANG	MAG	ANG	MAG	ANG	MAG	ANG		
0.1	0.301	-37.5	8.5	23.6	0.009	18.5	0.094	-66.4	5.9	18.6
0.2	0.209	-32.2	8.6	2.5	0.008	7.7	0.048	-61.5	7.0	18.7
0.4	0.194	-33.6	8.9	-17.8	0.008	0.1	0.029	-63.0	6.8	19.0
0.6	0.186	-40.0	9.0	-30.4	0.009	2.8	0.026	-69.6	6.0	19.1
0.8	0.183	-55.6	8.8	-45.6	0.010	-1.5	0.023	-83.6	5.6	18.8
1.0	0.185	-63.1	8.7	-58.1	0.009	1.6	0.022	-110.9	6.2	18.8
1.2	0.182	-79.7	8.7	-71.7	0.012	-7.3	0.030	-163.1	4.7	18.8
1.4	0.157	-94.8	8.5	-83.1	0.011	-20.0	0.034	116.6	5.2	18.6
1.6	0.159	-116.3	8.6	-95.5	0.009	-21.6	0.028	79.5	6.4	18.6
1.8	0.138	-128.1	8.4	-109.1	0.010	-21.9	0.028	69.1	5.9	18.5
2.0	0.135	-142.0	8.9	-123.1	0.009	-9.8	0.033	64.2	6.2	19.0
2.2	0.143	-156.0	8.5	-133.7	0.009	-22.2	0.039	52.6	6.5	18.5
2.4	0.150	-174.3	8.3	-148.1	0.009	1.1	0.039	40.8	6.6	18.4
2.6	0.158	163.8	8.2	-159.6	0.010	-22.8	0.047	38.8	6.0	18.2
2.8	0.172	154.7	8.2	-171.5	0.011	-22.0	0.056	34.8	5.4	18.3
3.0	0.189	137.1	8.0	173.5	0.014	-29.1	0.062	24.8	4.3	18.1
3.2	0.204	127.6	8.1	162.5	0.014	-27.6	0.071	16.6	4.2	18.2
3.4	0.200	111.4	7.8	148.6	0.015	-35.1	0.082	9.5	4.1	17.9
3.6	0.216	107.3	7.8	136.0	0.017	-35.4	0.088	-1.4	3.6	17.8
3.8	0.229	94.0	7.7	123.4	0.019	-38.1	0.099	-12.2	3.3	17.7
4.0	0.231	83.3	7.3	109.8	0.022	-47.6	0.110	-25.0	2.9	17.3
4.2	0.226	77.8	7.3	96.6	0.025	-55.7	0.118	-43.0	2.6	17.3
4.4	0.207	70.2	6.8	84.4	0.027	-62.1	0.127	-64.2	2.6	16.7
4.6	0.164	75.8	6.6	74.8	0.031	-84.1	0.116	-99.6	2.4	16.4
4.8	0.212	89.0	6.8	67.6	0.029	-100.3	0.070	-145.6	2.5	16.7
5.0	0.305	85.6	7.1	51.7	0.022	-100.7	0.013	176.5	3.0	17.1

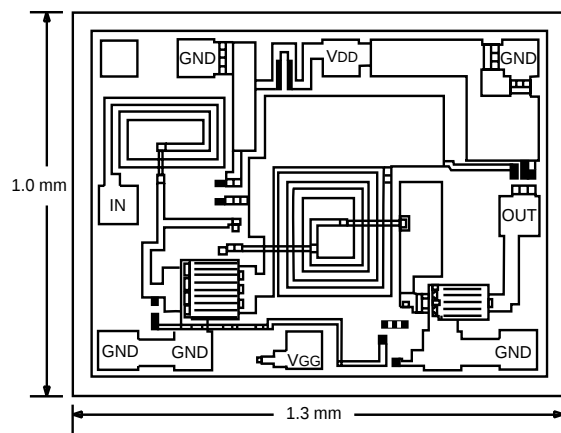
OUTLINE DIMENSIONS (Units in mm)



LEAD CONNECTIONS:

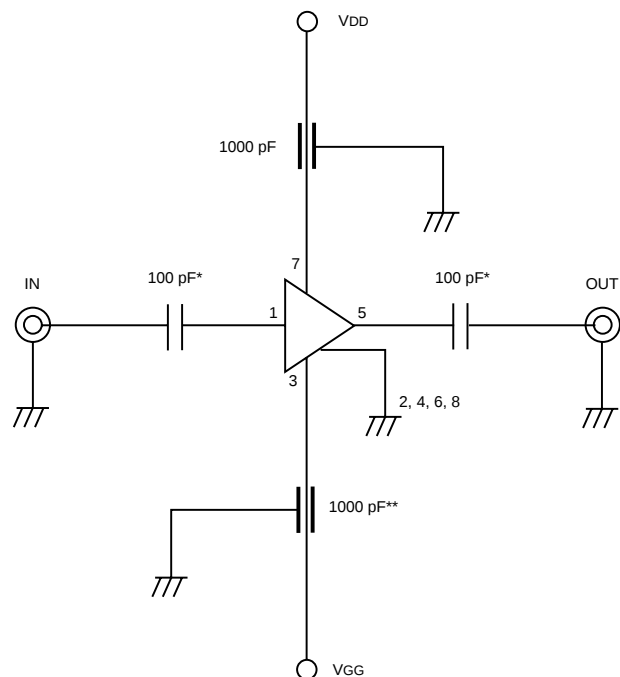
- | | |
|--------------------|--------------------|
| 1. INPUT | 5. OUTPUT |
| 2. GND | 6. GND |
| 3. V _{GG} | 7. V _{DD} |
| 4. GND | 8. GND |

UPG100P (CHIP)



Notes: Bonding Pad Size: 100 μ m Square
Distance between Bonding Pad Outer Edge and Die Edge:
70 μ m Typical
Chip Thickness: 140±10 μ m

TEST CIRCUIT



* Chip Capacitor

**Recommended when cascading UPG100 with NEC's UPG100, 101, 103B's.

RECOMMENDED CHIP ASSEMBLY CONDITIONS

DIE ATTACHMENT

Atmosphere: N₂ gas
Temperature: 320±5°C
AuSn Preform: 0.5 x 0.5 x 0.05^t (mm), 1 piece

The hard solder such as AuSi or AuGe which has higher melting point than AuSn should not be used.
Epoxy Die Attach is not recommended.

Base Material: CuW, Cu, Kovar (Other material should not be used)

BONDING

Machine: Thermo-compression bonding. Ultrasonic bonding is not recommended.
Wire: 30 μ m diameter Au wire, 10 wires
Temperature: 260±5°C
Strength: 31±3g
Atmosphere: N₂ gas

It is critical that GND points be connected to the ground with the shortest possible wire.

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